

Day : Tuesday
Date: 6/15/2004


PALM INTRANET

Time: 09:00:32

Inventor Name Search Result

Your Search was:

Last Name = ADEL

First Name = MICHAEL

Application#	Patent#	Status	Date Filed	Title	Inventor Name 49
<u>60546546</u>	Not Issued	020	02/20/2004	APPARATUS AND METHODS FOR DETERMINING OVERLAY AND USES OF SAME	ADEL, MICHAEL E.
<u>60546024</u>	Not Issued	020	02/18/2004	APPARATUS AND METHODS FOR DETERMINING OVERLAY AND USES OF SAME	ADEL, MICHAEL E.
<u>60544292</u>	Not Issued	020	02/12/2004	DISPENSING STATION	ADELL, MICHAEL L.
<u>60506281</u>	Not Issued	020	09/26/2003	STRUCTURES AND METHODS FOR OVERLAY METROLOGY	ADEL, MICHAEL
<u>60498524</u>	Not Issued	020	08/27/2003	METHOD AND APPARATUS COMBINING IMAGING AND SCATTEROMETRY FOR OVERLAY METROLOGY	ADEL, MICHAEL
<u>60484627</u>	Not Issued	020	07/02/2003	APPARATUS AND METHODS FOR PROVIDING IN-CHIP MICROTARGETS FOR METROLOGY OR INSPECTION	ADEL, MICHAEL E.
<u>60456681</u>	Not Issued	020	03/19/2003	USE OF OVERLAY DIAGNOSTICS FOR ENHANCED AUTOMATIC PROCESS CONTROL	ADEL, MICHAEL E.
<u>60435878</u>	Not Issued	020	12/19/2002	METHOD OF DETERMINING THE FIDELITY OR ROBUSTNESS OF AN OVERLAY MARK	ADEL, MICHAEL
<u>60419786</u>	Not Issued	020	10/17/2002	OVERLAY METROLOGY	ADEL, MICHAEL
<u>60395847</u>	Not	159	07/11/2002	USE OF OVERLAY	ADEL, MICHAEL

	Issued			DIAGNOSTICS FOR ENHANCED AUTOMATIC PROCESS CONTROL	
<u>60386285</u>	Not Issued	159	06/05/2002	USE OF OVERLAY DIAGNOSTICS FOR ENHANCED AUTOMATIC PROCESS CONTROL	ADEL, MICHAEL
<u>60357390</u>	Not Issued	159	02/15/2002	OVERLAY METROLOGY	ADEL, MICHAEL
<u>60301763</u>	Not Issued	159	06/27/2001	OVERLAY MARKS, METHOD OF OVERLAY MARK DESIGNED AND METHODS OF OVERLAY MEASUREMENTS	ADEL, MICHAEL
<u>60301613</u>	Not Issued	159	06/27/2001	OVERLAY MARKS, METHOD OF OVERLAY MARK DESIGNED AND METHODS OF OVERLAY MEASUREMENTS	ADEL, MICHAEL
<u>60301591</u>	Not Issued	159	06/27/2001	OVERLAY MARKS, METHOD OF OVERLAY MARK DESIGNED AND METHODS OF OVERLAY MEASUREMENTS	ADEL, MICHAEL
<u>60301484</u>	Not Issued	159	06/27/2001	OVERLAY MARKS, METHOD OF OVERLAY MARK DESIGNED AND METHODS OF OVERLAY MEASUREMENTS	ADEL, MICHAEL
<u>10785821</u>	Not Issued	019	02/23/2004	APPARATUS AND METHODS FOR DETECTING OVERLAY ERRORS USING SCATTEROMETRY	ADEL, MICHAEL
<u>10785732</u>	Not Issued	019	02/23/2004	APPARATUS AND METHODS FOR DETECTING OVERLAY ERRORS USING SCATTEROMETRY	ADEL, MICHAEL
<u>10785731</u>	Not Issued	019	02/23/2004	APPARATUS AND METHODS FOR DETECTING OVERLAY ERRORS USING SCATTEROMETRY	ADEL, MICHAEL
<u>10785723</u>	Not Issued	019	02/23/2004	APPARATUS AND METHODS FOR DETECTING OVERLAY ERRORS USING SCATTEROMETRY	ADEL, MICHAEL
<u>10785430</u>	Not	019	02/23/2004	APPARATUS AND METHODS	ADEL, MICHAEL

	Issued			FOR DETECTING OVERLAY ERRORS USING SCATTEROMETRY	
<u>10785396</u>	Not Issued	019	02/23/2004	APPARATUS AND METHODS FOR DETECTING OVERLAY ERRORS USING SCATTEROMETRY	ADEL, MICHAEL
<u>10785395</u>	Not Issued	019	02/23/2004	APPARATUS AND METHODS FOR DETECTING OVERLAY ERRORS	ADEL, MICHAEL
<u>10729838</u>	Not Issued	018	12/05/2003	APPARATUS AND METHOD FOR DETECTING OVERLAY ERRORS USING SCATTEROMETRY	ADEL, MICHAEL
<u>10438963</u>	Not Issued	030	05/14/2003	USE OF OVERLAY DIAGNOSTICS FOR ENHANCED AUTOMATIC PROCESS CONTROL	ADEL, MICHAEL E.
<u>10438962</u>	Not Issued	030	05/14/2003	USE OF OVERLAY DIAGNOSTICS FOR ENHANCED AUTOMATIC PROCESS CONTROL	ADEL, MICHAEL E.
<u>10423827</u>	Not Issued	030	04/25/2003	METHOD AND MARK FOR METROLOGY OF PHASE ERRORS ON PHASE SHIFT MASKS	ADEL, MICHAEL
<u>10367124</u>	Not Issued	020	02/13/2003	OVERLAY METROLOGY AND CONTROL METHOD	ADEL, MICHAEL
<u>10186324</u>	Not Issued	030	06/26/2002	OVERLAY MARKS, METHODS OF OVERLAY MARK DESIGN AND METHODS OF OVERLAY MEASUREMENTS	ADEL, MICHAEL
<u>10185737</u>	Not Issued	071	06/26/2002	OVERLAY MARKS, METHODS OF OVERLAY MARK DESIGN AND METHODS OF OVERLAY MEASUREMENTS	ADEL, MICHAEL
<u>10184026</u>	Not Issued	030	06/26/2002	OVERLAY MARKS, METHODS OF OVERLAY MARK DESIGN AND METHODS OF OVERLAY MEASUREMENTS	ADEL, MICHAEL
<u>10184013</u>	Not Issued	030	06/26/2002	OVERLAY MARKS, METHODS OF OVERLAY MARK DESIGN AND	ADEL, MICHAEL

				METHODS OF OVERLAY MEASUREMENTS	
<u>09894987</u>	Not Issued	030	06/27/2001	OVERLAY MARKS, METHODS OF OVERLAY MARK DESIGN AND METHODS OF OVERLAY MEASUREMENTS	ADEL, MICHAEL
<u>09752833</u>	<u>6419361</u>	150	01/03/2001	SPECTRAL BIO-IMAGING OF THE EYE	ADEL, MICHAEL
<u>09194196</u>	<u>6556853</u>	150	11/20/1998	SPECTRAL BIO-IMAGING OF THE EYE	ADEL, MICHAEL
<u>09143964</u>	<u>6142629</u>	150	08/30/1998	SPECTRAL IMAGING USING ILLUMINATION OF PRESELECTED SPECTRAL CONTENT	ADEL, MICHAEL E.
<u>08947502</u>	<u>6082892</u>	150	10/10/1997	TEMPERATURE MEASURING METHOD AND APPARATUS	ADEL, MICHAEL E.
<u>08942122</u>	<u>6198532</u>	150	10/01/1997	SPECTRAL BIO-IMAGING OF THE EYE	ADEL, MICHAEL
<u>08786739</u>	<u>5697852</u>	150	01/27/1997	METHOD AND MEANS FOR PACKAGING CUE TIP CHALK	ADELSON, MICHAEL L.
<u>08776063</u>	<u>5856871</u>	150	01/21/1997	FILM THICKNESS MAPPING USING INTERFEROMETRIC SPECTRAL IMAGING	ADEL, MICHAEL E.
<u>08604997</u>	<u>5823681</u>	150	02/29/1996	MULTIPOINT TEMPERATURE MONITORING APPARATUS FOR SEMICONDUCTOR WAFERS DURING PROCESSING	ADEL, MICHAEL E.
<u>08392010</u>	Not Issued	161	02/21/1995	TEMPERATURE MEASURING METHOD AND APPARATUS	ADEL, MICHAEL E.
<u>08066257</u>	Not Issued	161	05/25/1993	TEMPERATURE MEASURING METHOD AND APPARATUS	ADEL, MICHAEL E.
<u>08057592</u>	<u>5330875</u>	250	05/05/1993	PROCESS FOR PRODUCING NEGATIVE AND POSITIVE ORIGINAL IMAGES ON A BI-LEVEL PRINTING PLATE UTILIZING NON-SILVER HALIDE LAYER AND SILVER HALIDE OVERLAYER	ADELMAN, MICHAEL W.
<u>08010038</u>	<u>5322361</u>	250	01/28/1993	METHOD AND APPARATUS FOR MEASURING TEMPERATURE	ADEL, MICHAEL E.
<u>07756038</u>	<u>5469866</u>	150	09/06/1991	PACKAGING FOR A	ADELL, MICHAEL

				CONSUMER PRODUCT	
<u>07566577</u>	Not Issued	161	08/13/1990	METHOD AND APPARATUS FOR INDICATING SPATIAL DIRECTION OF AN INVISIBLE LASER BEAM	ADEL , MICHAEL E.
<u>07427823</u>	5063940	150	10/26/1989	MOUTHGUARD PACKAGING	ADELL , MICHAEL
<u>06004840</u>	4399979	150	01/19/1979	DEVICE FOR SELF-TAILING A CONVENTIONAL WINCH DRUM	ADELMAN , MICHAEL R.

[Search and Display More Records.](#)

	Last Name	First Name	
Search Another: Inventor	<input type="text" value="ADEL"/>	<input type="text" value="MICHAEL"/>	<input type="button" value="Search"/>

To go back use Back button on your browser toolbar.

Back to [PALM](#) | [ASSIGNMENT](#) | [OASIS](#) | [Home page](#)